Algorithmic Macromodelling Methods for Mixed-Signal Systems

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University of Minnesota

ECE Dept, U of M

- $\sim$ 44 faculty in several areas
  - Communications: Alouini, Giannakis, Kaveh, Tewfik
  - Comp. Arch.: Lilja, Kinney
  - Signal Proc/DSP: Ebbini, Moon, Parhi
  - Devices/Nano: Cambell, Cohen, Kiehl, Nathan, Jacobs
  - Optics/MEMS: Gopinath, Leger, Talgadher
  - Controls/Image Proc: Georgiou, Sapiro

ECE Dept, U of M

- CAD, Analog Design
  - Bazargan: FPGAs, reconfigurable computing, physical design
  - Harjani: RF and mixed-signal design
  - Sapatnekar: Physical design, timing, delay, crosstalk
  - Roychowdhury: Analog/system verification

Analog System Verification Group

- Students: 5 PhD, 1 MS; undergraduates
- Projects:
  - Automated nonlinear macromodelling
  - Digital-to-analog substrate noise prediction
  - Oscillator/PLL macromodelling/simulation
  - Multi-time methods, robust envelope techniques
  - Fast fiber simulation
  - Prototyping infrastructure
- Funding/Collaborations: NSF, SRC, DARPA, Fujitsu, Sandia, IBM, TI, Agilent

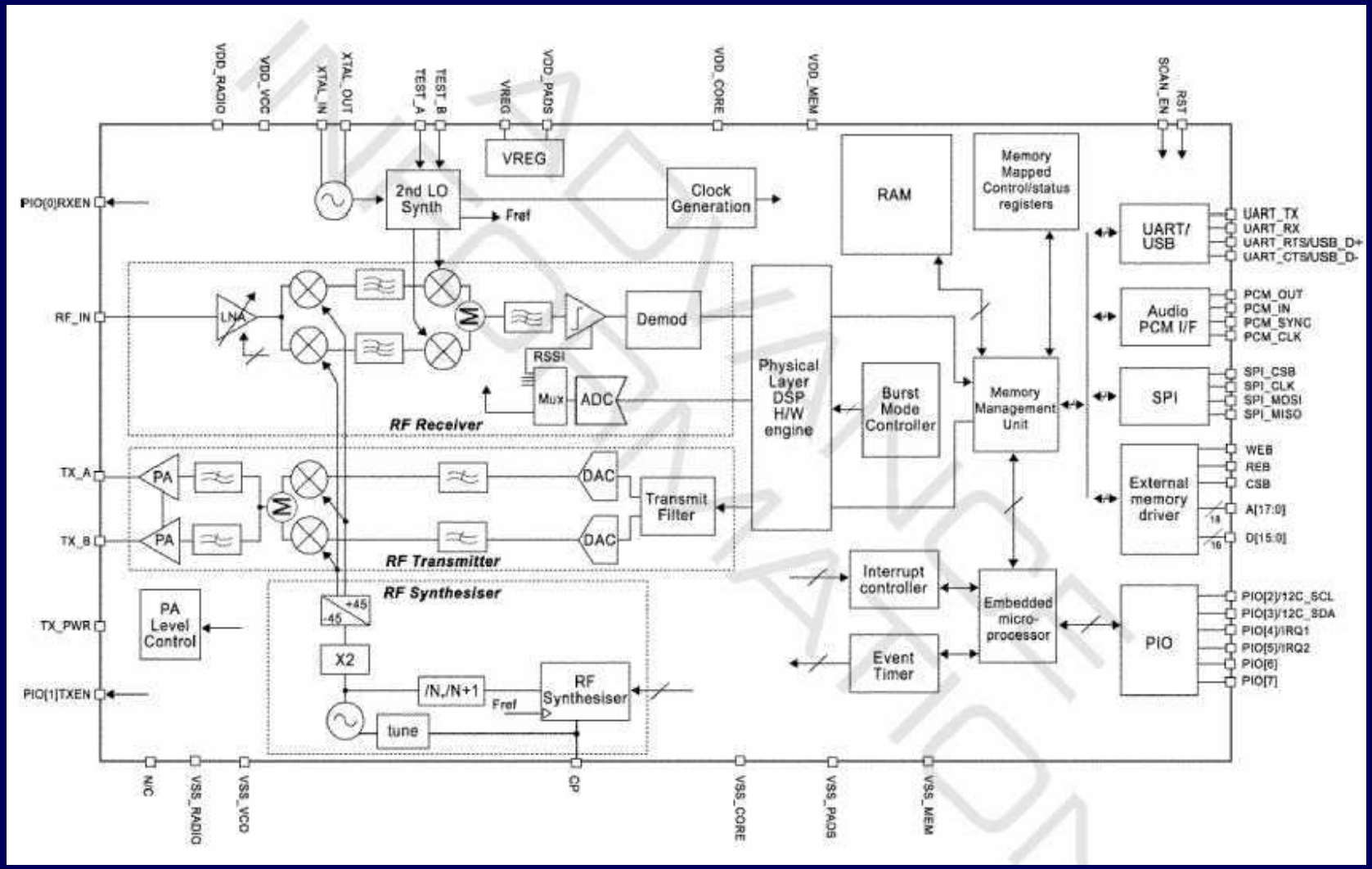
Market Trend: Portable Devices

- Proliferation of small, cheap, ubiquitous devices
  - cellphones, PDAs, wireless LANs, Bluetooth
  - GSM, TDMA, CDMA, 802.11b/g/a, 2.5G
  - next: 3G, UMTS
- 2 billion users worldwide by 2007
  - India: 28M users (Dec 2003), 100M by 2005
  - Max growth rate: SE Asia, China
  - US: tenfold growth by 2005 (??)
    - $22-$140B (IDC, Merrill-Lynch)
    - exceed PC growth over 1980s: **Intel**

Drivers for Demand

- Price
  - India: 2.1M new subscribers in Dec 2003
    - “driven by some of the lowest tariffs in the world”
- Time-to-market
  - competitive pressures
- Design challenge: **mixed-signal/RF blocks**
  - the main design bottleneck

Bluetooth mixed-signal RFIC



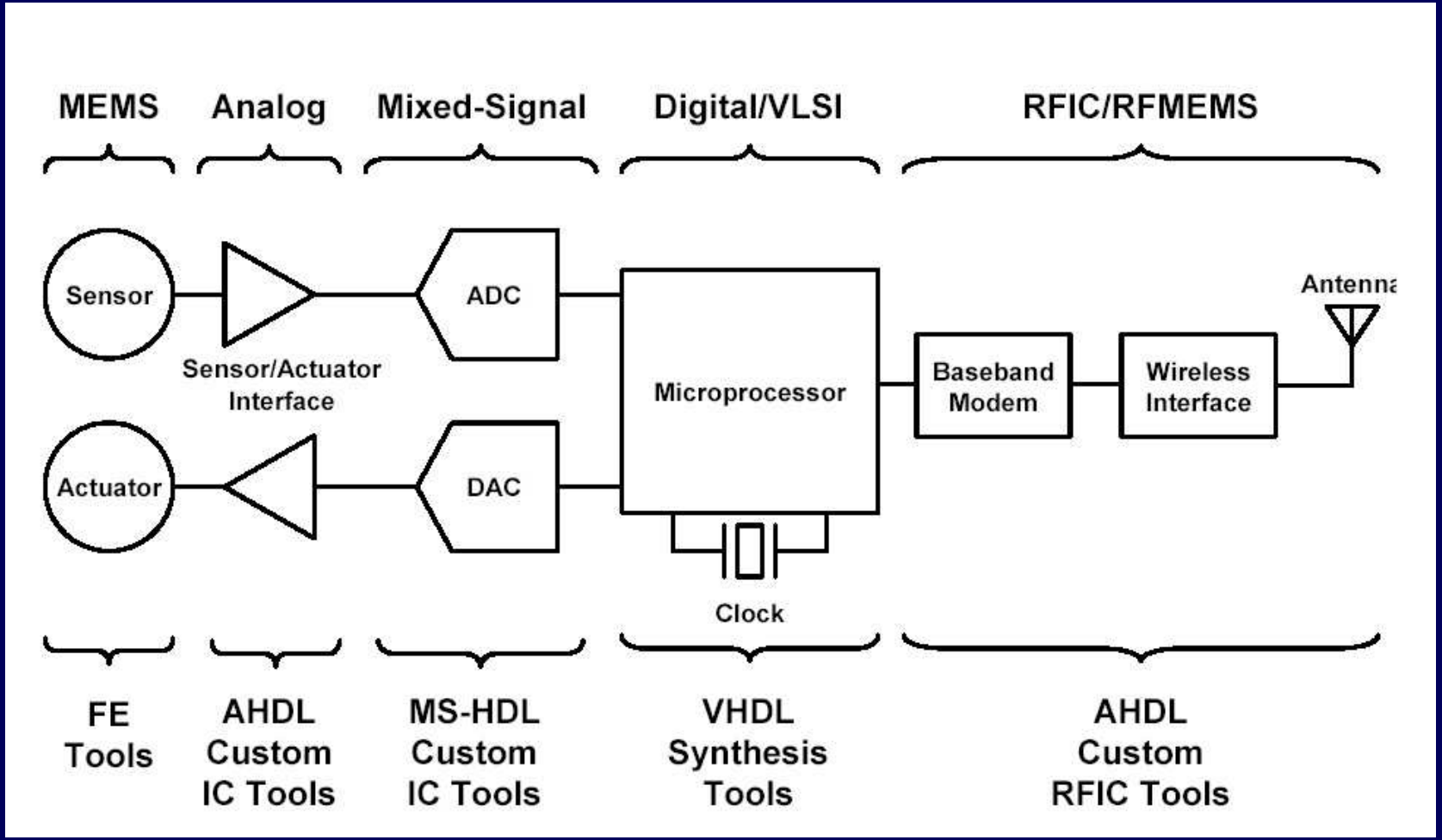
Cambridge Silicon

☛Cheap ☛Low margins☛ **Must work first time**

Verification Challenges

- Large entire systems to verify
- Interactions between blocks, “second-order effects”
- Interconnect, coupling, noise
- Speed with SPICE-like accuracy becoming necessity
- **Impossible at SPICE level**

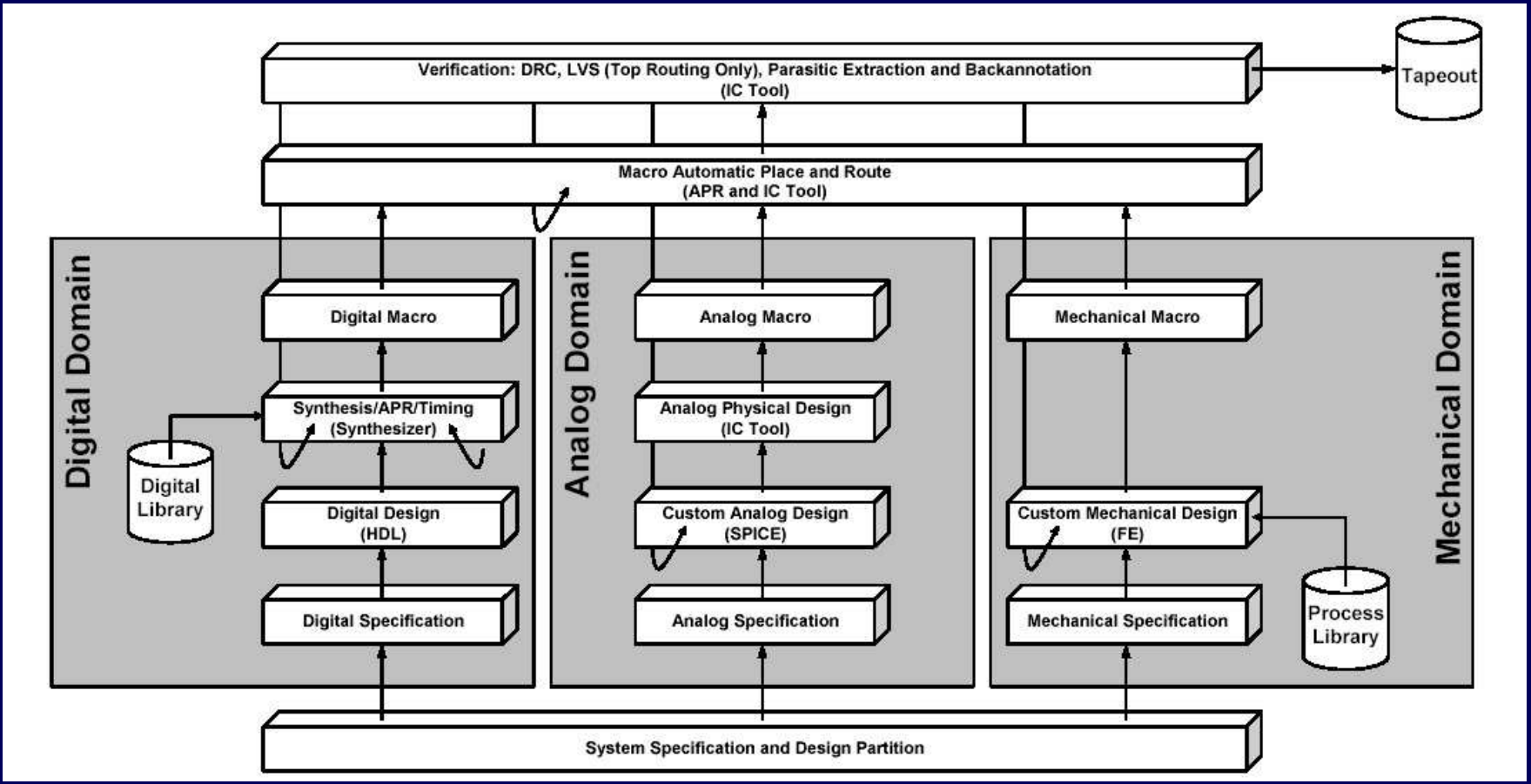
MEMS Sensor System



McCorquodale et al, U of Michigan

☛Multiple physical domains to model

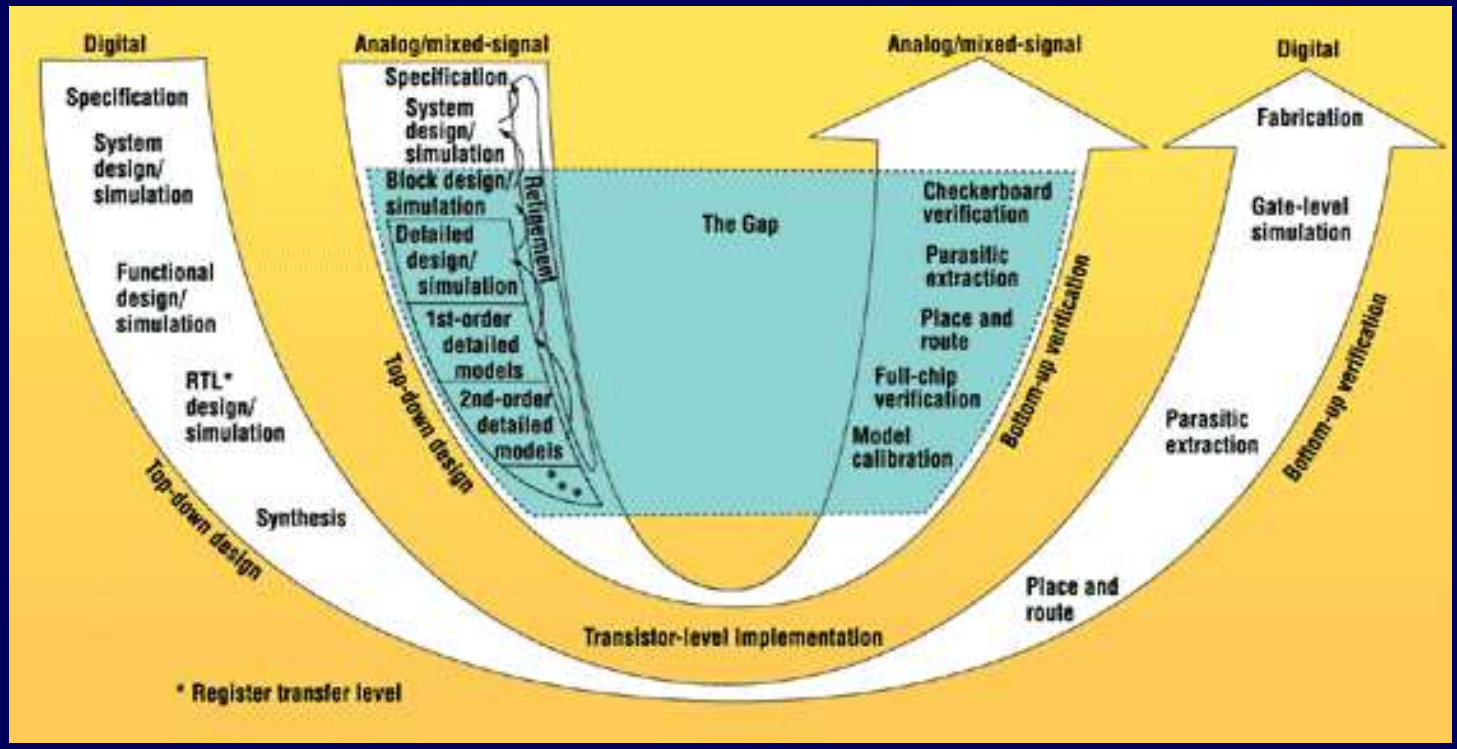
Today's bottom-up design



McCorquodale et al, U of Michigan

☛3-5 spins = cutting edge; >10 at Lucent

"The Gap"



EE Times

"The primary problem hindering the change to analog top-down design and bottom-up verification has been the **lack of tool support for the design process between system-level specification and transistor-level implementation**, as well as between transistor implementation and chip fabrication. These missing tools are commonly referred to as The Gap." - EE Times, 2001

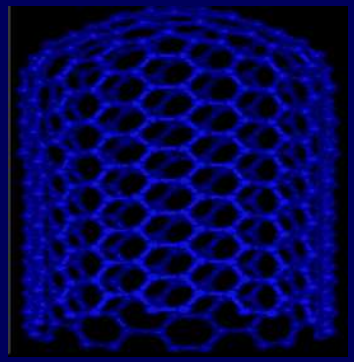
“The Gap”

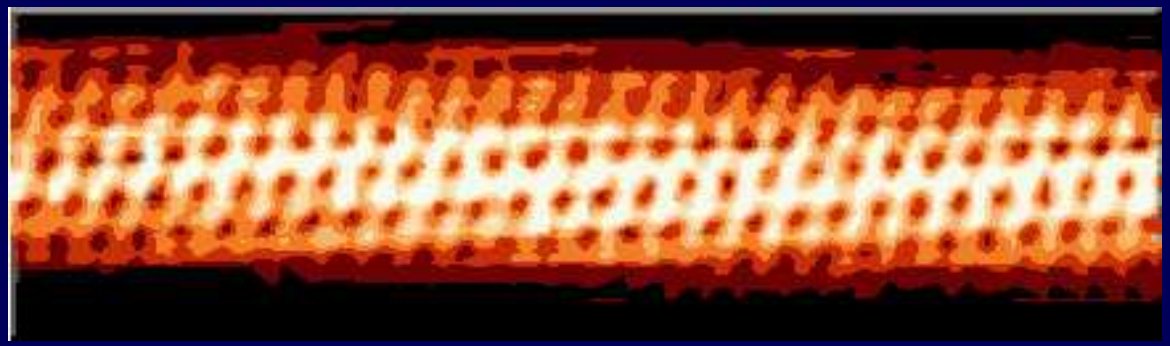
☛Solution: **good bottom-up macromodels**

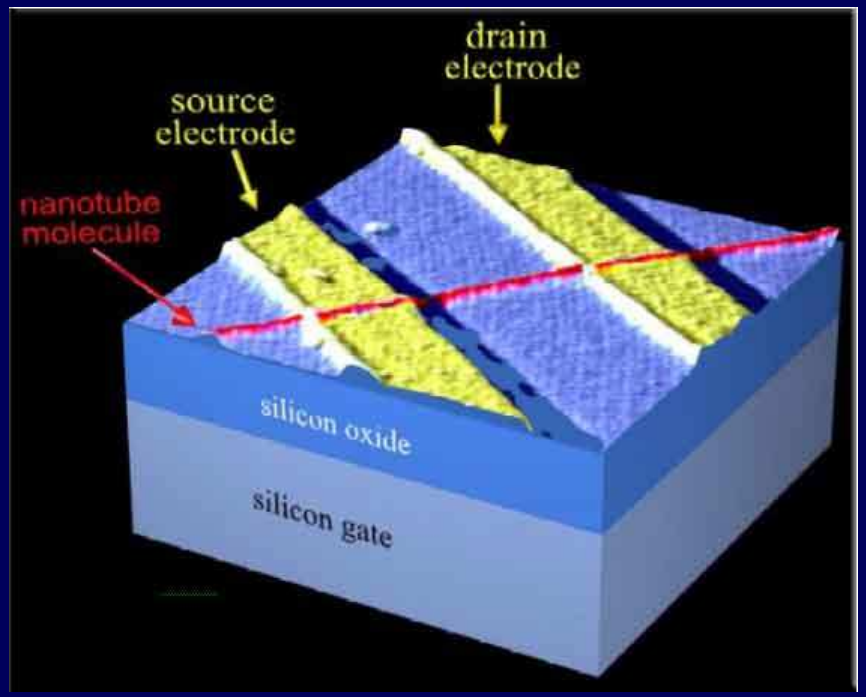
Generating Macromodels

- Today: **manually**
- Highly skilled activity
  - what if designer leaves?
- Mistakes (esp “second-order”)
- Time-consuming
- Tomorrow: myriad new technologies
  - Modelling expertise in short supply

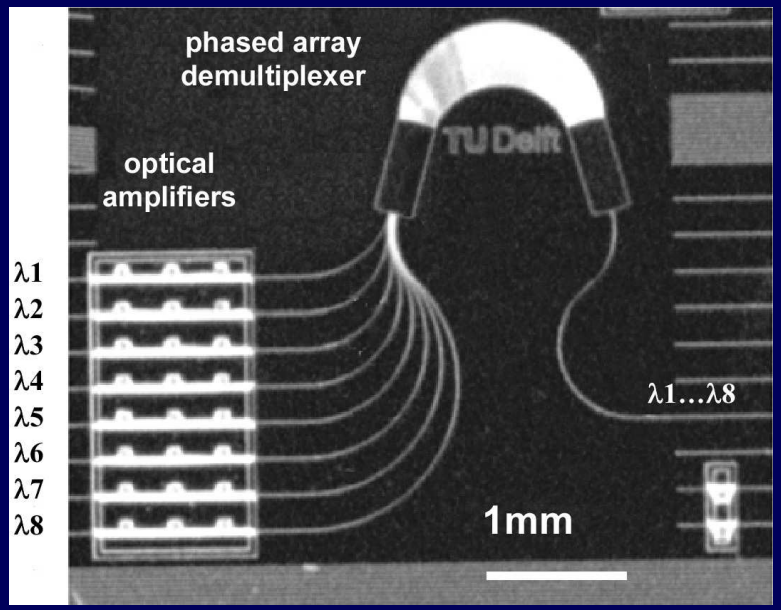
Carbon Nanotubes



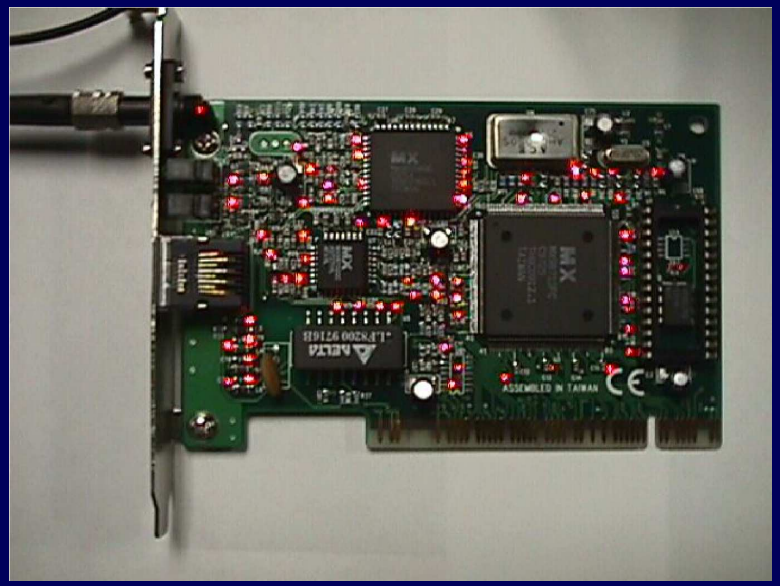




Integrated Opto-electronics



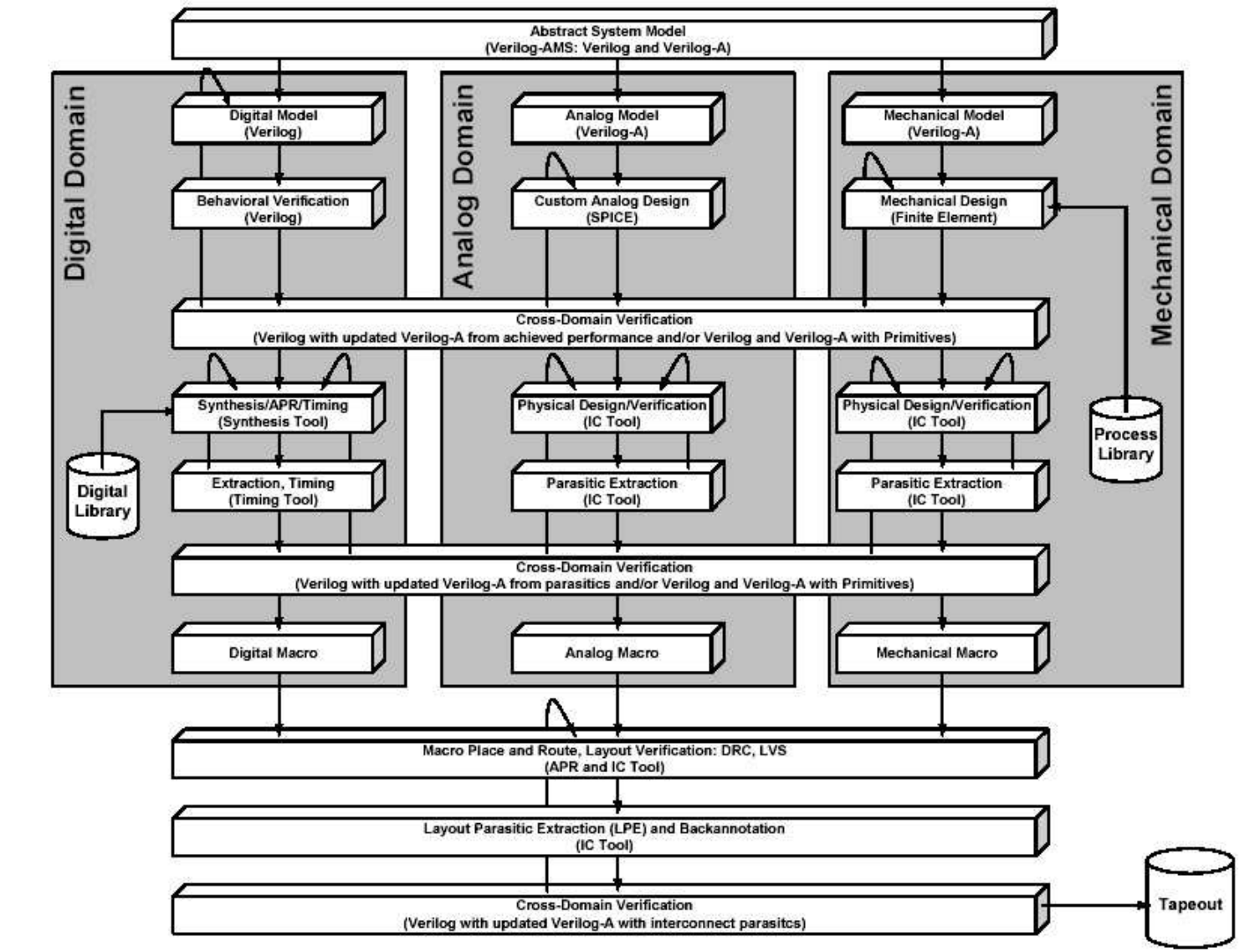
TU Delft


Ray Chen, UT Austin

- More domains to macromodel at system level

☛Manual expertise scarce: **general automated capability**?

Top-down Design



McCorquodale et al, U of Michigan

Automated Macromodelling

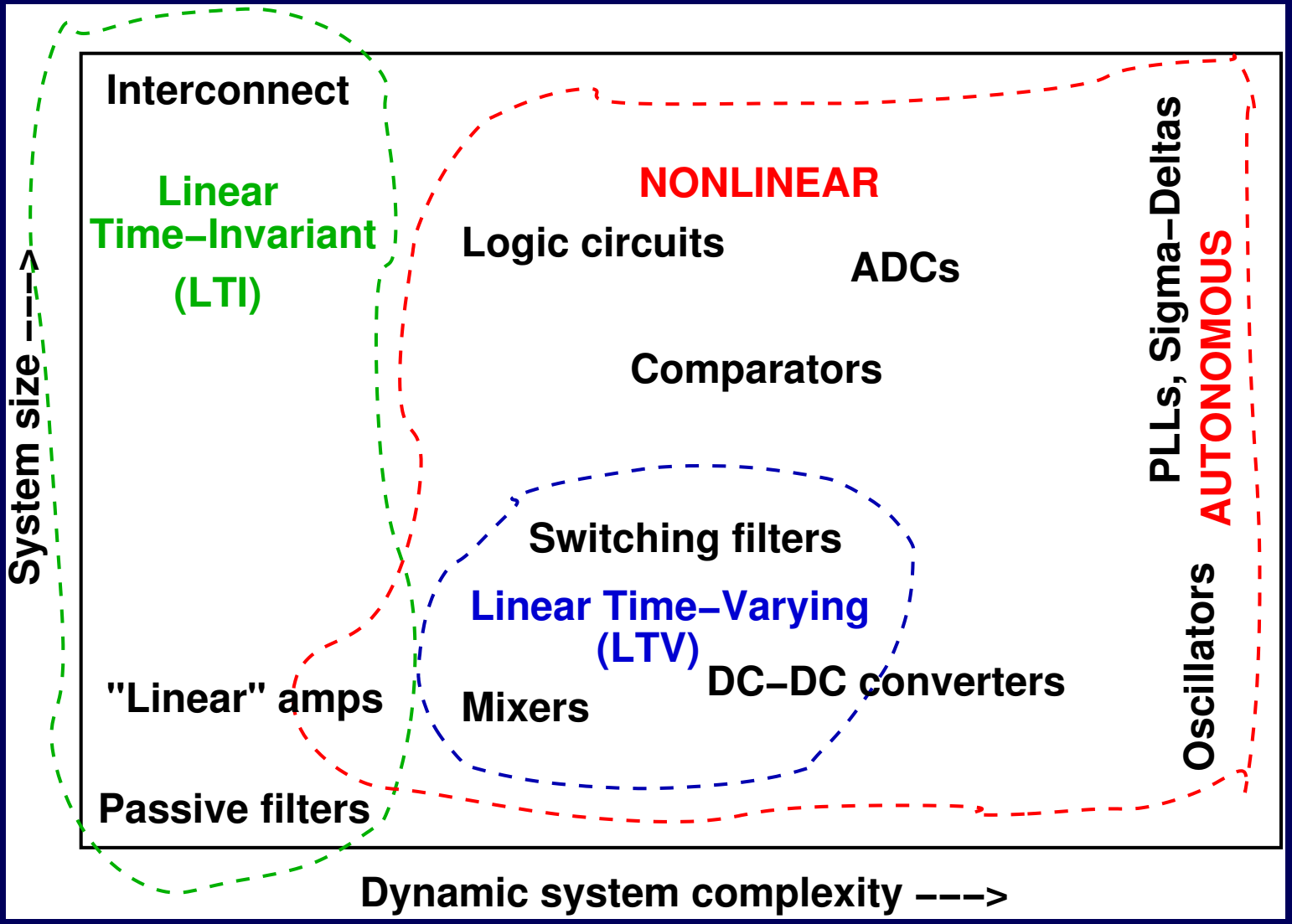
- The dream: **push-button bottom-up model generation**
  - prescribed accuracy guaranteed
  - trade-off speed vs accuracy
- **Needed** for design sustainability
  - complexity exceeds manual ability to keep up

The Difficulty

"At this point, you may wonder why you should bother with behavioral libraries and calibration. Why not just **submit the transistor-level design to some smart software and let it come up with a model**? Unfortunately, despite some claims to the contrary, **practical model synthesis is still a long way off**. Attempts at this technology rely on **pre-existing templates, which are unlikely to exist for leading-edge or proprietary designs**. There's **no pushbutton approach to analog modeling**, and from all indications, **this will remain the case for some time to come**." - EE Times, 2001

- Perhaps not quite so bleak!
- Automated macromodel generation **is** difficult

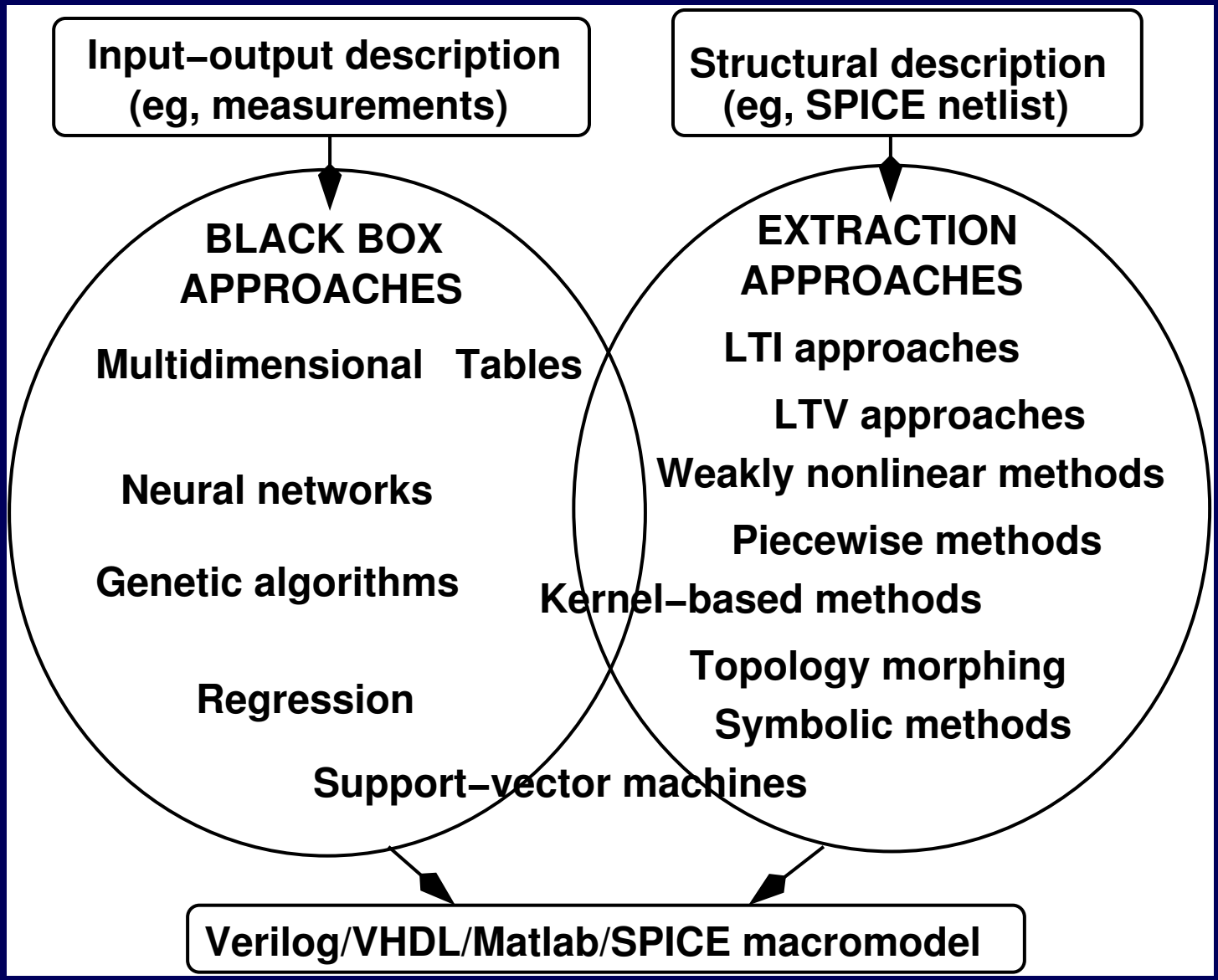
Why Difficult?



Approaches to Macromodelling

- **Black-box** problems
  - samples of input-output pairs
  - measurement and/or simulation
  - **paucity of information**
- **Extraction (bottom-up reduction)** problems
  - Detailed circuit/system info available
  - eg, SPICE netlist: **differential equations**
  - **surfeit of information**
  - **potential for better macromodels**

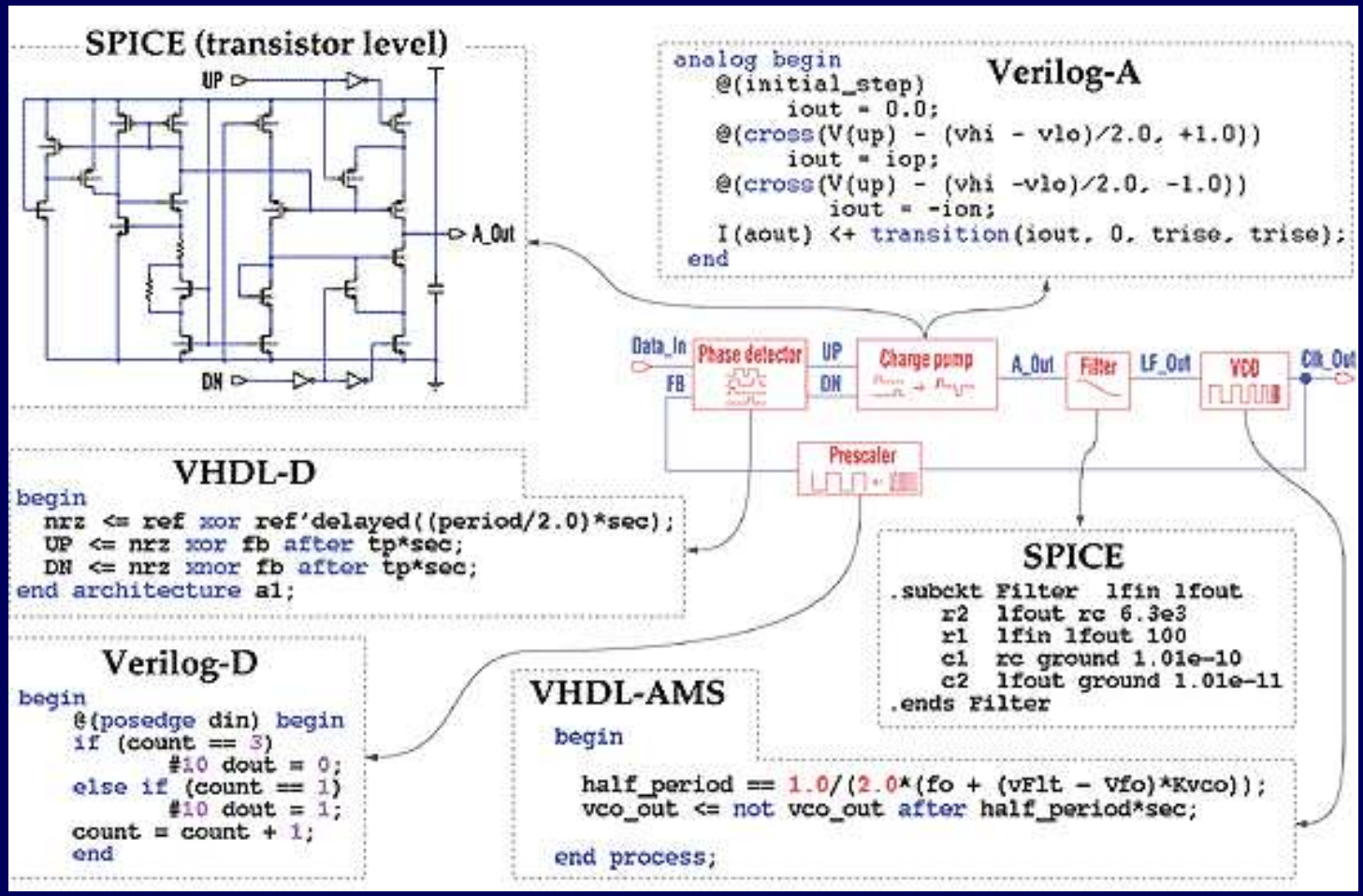
Automated MM Approaches



Macromodelling Languages

- Output of macromodelling process
- AHDL Languages - eg, Verilog-A, VHDL-AMS
  - the EDA choice
- Matlab/Simulink
  - widely used by designers
- SPICE(?)
- **Fundamentally**: (integro-)differential-algebraic equations

Macromodelling Languages



EE Times

☛Multiplicity of languages, should inter-operate

“Algorithmic” MM Approaches

- Mathematical algorithms based on theory
- Provably preserve some useful property
  - eg, moments of transfer function
- **AWE:** first prominent method (LTI)
- PVL, PRIMA, TBR methods (all LTI)
- Variety of nonlinear, LTV methods
- **Generally applicable** (eg, multi-physics)

Linear Time Invariant Systems

- What is LTI?
  - Scale input waveform $\Rightarrow$ scale output waveform
  - Time-shift input $\Rightarrow$ time-shift output
- **Interconnect**, "linear" circuit elements
- Well understood: 50 years of theory
  - Laplace transforms, LTI ODEs, controllability/observability, ...
  - Powers hand analysis by most designers

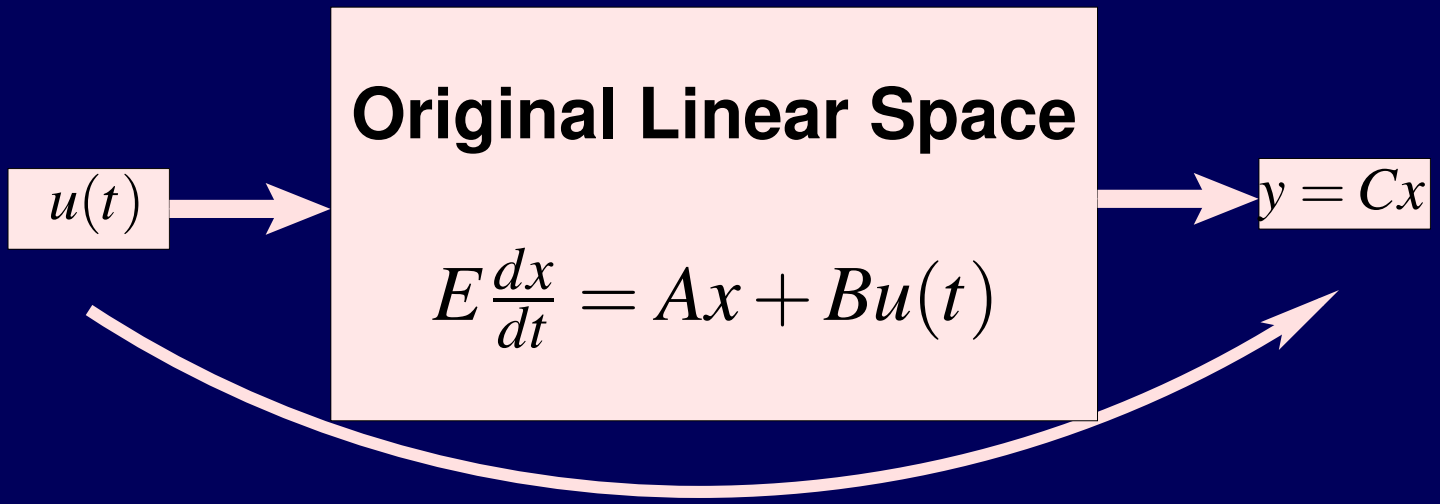
Asymptotic Waveform Evaluation

- AWE (Pillage/Rohrer ~1990)
- **Preserve moments** of LTI **transfer function**
  - frequency-domain xfer-fn derivatives
  - time-domain rise/fall time interpretations
- **Explicit moment matching**
  - calculate moments of original system
  - solve (linear matrix) equations to get small rational-function macromodel

LTI MM Accuracy/Scalability

- Increasing size does not increase accuracy
  - Explicit moment generation, Hankel-matrix-based calculation numerically ill-conditioned
- **Implicit moment matching**: Krylov-subspace methods
  - don't calculate moments: generate related Krylov subspaces robustly (Lanczos/Arnoldi methods)
  - generate macromodels directly - moments matched implicitly
- Pade-via-Lanczos **(PVL**, Feldmann/Freund ~1994/5)

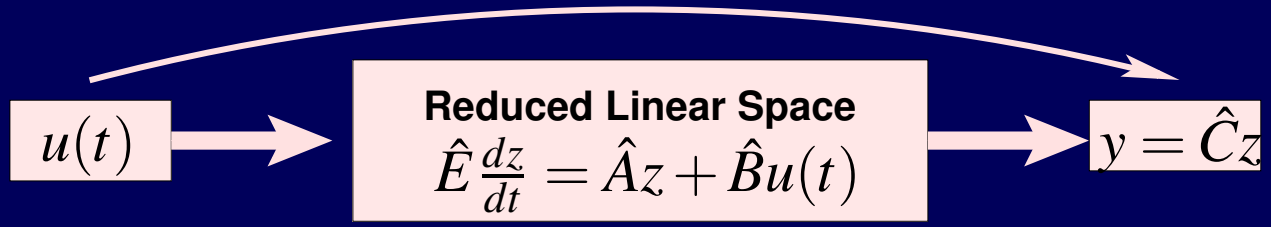
LTI MM Generation



$$H(s) = C(sE - A)^{-1}B$$

$$x = Vz, x \in \mathbf{R^n}, \mathbf{z} \in \mathbf{R^q}$$

$$\hat{H}(s) = \hat{C}(s\hat{E} - \hat{A})^{-1}\hat{B}$$



LTI MM Stability/Passivity

- Interconnect: basically R, L, C elements
  - **Passive**: can't generate energy
- But macromodels can!
  - small inaccuracies in MM parameters $\Rightarrow$ qualitative stability problems $\Rightarrow$ useless MM!
  - must preserve passivity
- Passivity for RC, RLC circuits
  - Congruence transformations (Kerns/Yang 95)
  - PRIMA (Odabasioglu/Celik/Pileggi, 97)
  - Others: PVL extensions, beyond RLC ...

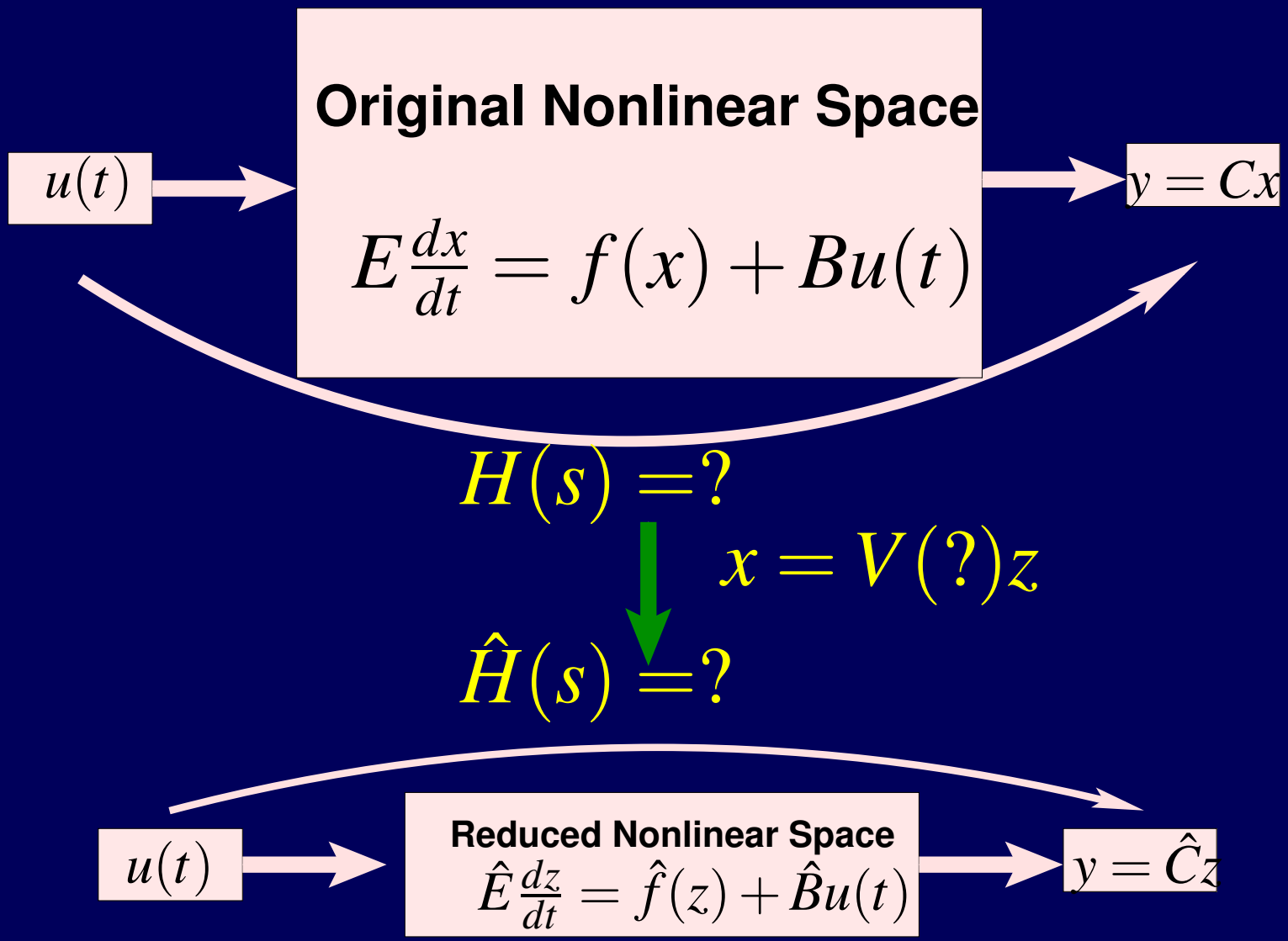
LTI MM Optimality/Compactness

- Truncated Balanced Realizations (TBR)
  - Silveira/White et al
  - Trim internal states that are not **controllable/observable**
  - Provably optimal: minimizes I/O norm error for given MM size
- But: computationally expensive
  - cubic in original size
- Mix and match: Krylov + TBR (Phillips et al 02)
  - First create big (~100s) MM via Krylov
  - Use TBR to make compact MM

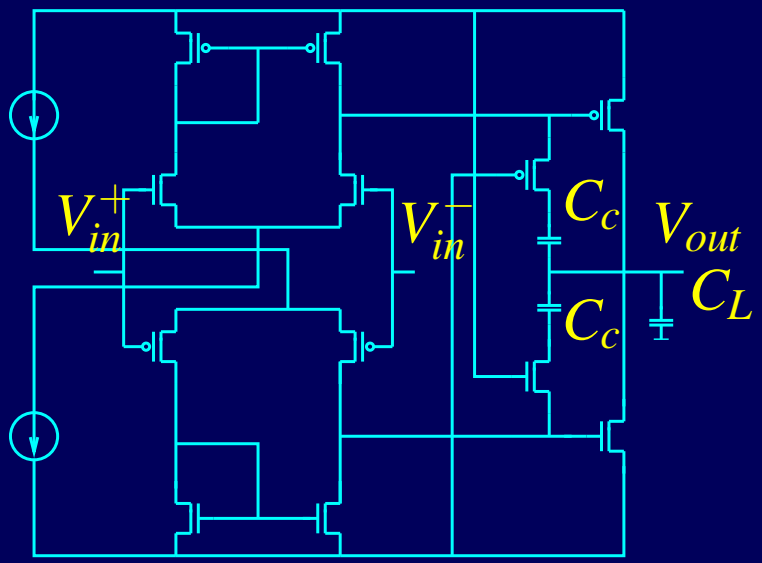
LTI MM Summary

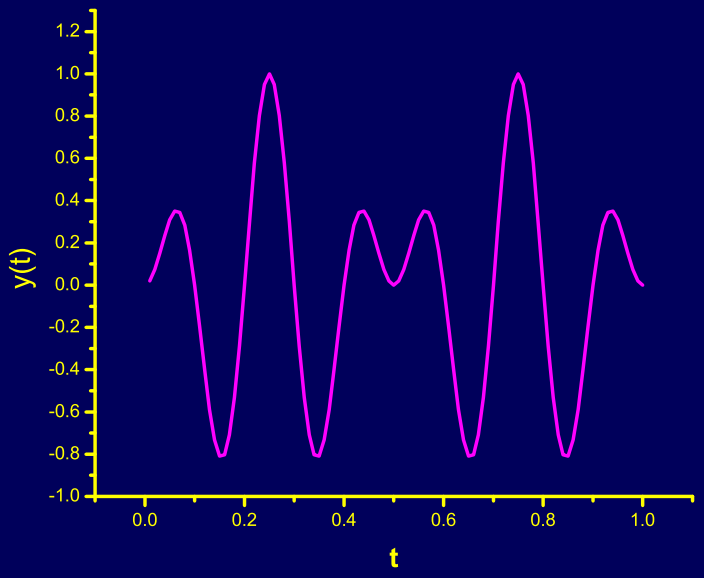
- Important features
  - Accuracy vs size tradeoff
  - MM scalability
  - MM passivity
- Computational properties
  - AWE, Krylov methods linear with original size
  - TBR methods cubic
- Relatively mature and practically usable
- Basis for nonlinear approaches

Nonlinear Macromodelling

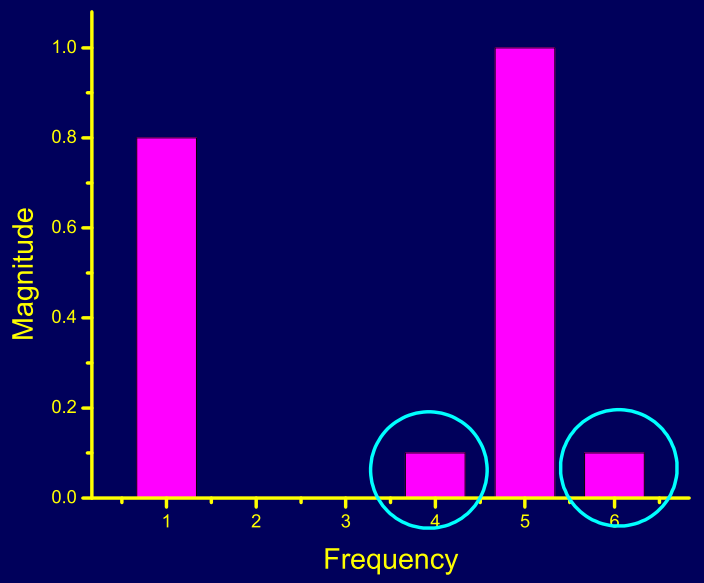


Weakly Nonlinear Systems



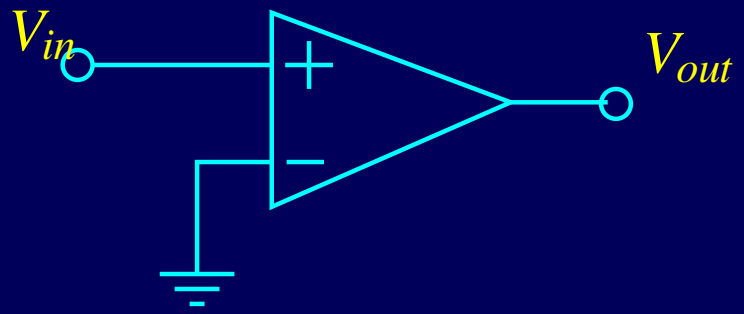


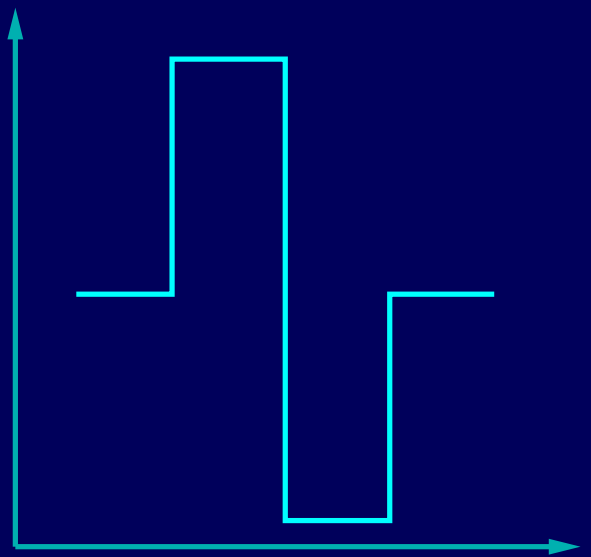
- Must capture small distortion/IM

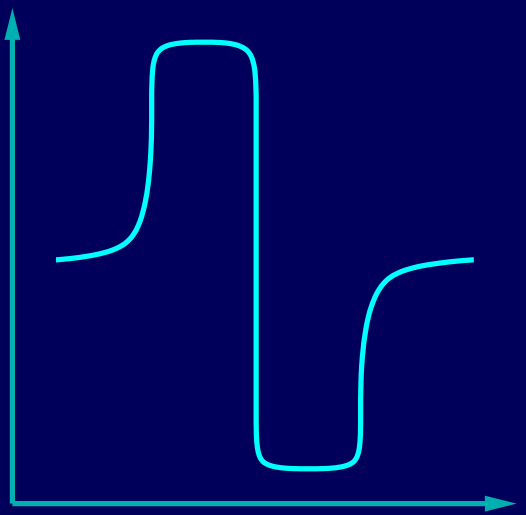


Strong Nonlinearities

Comparators, switching mixers



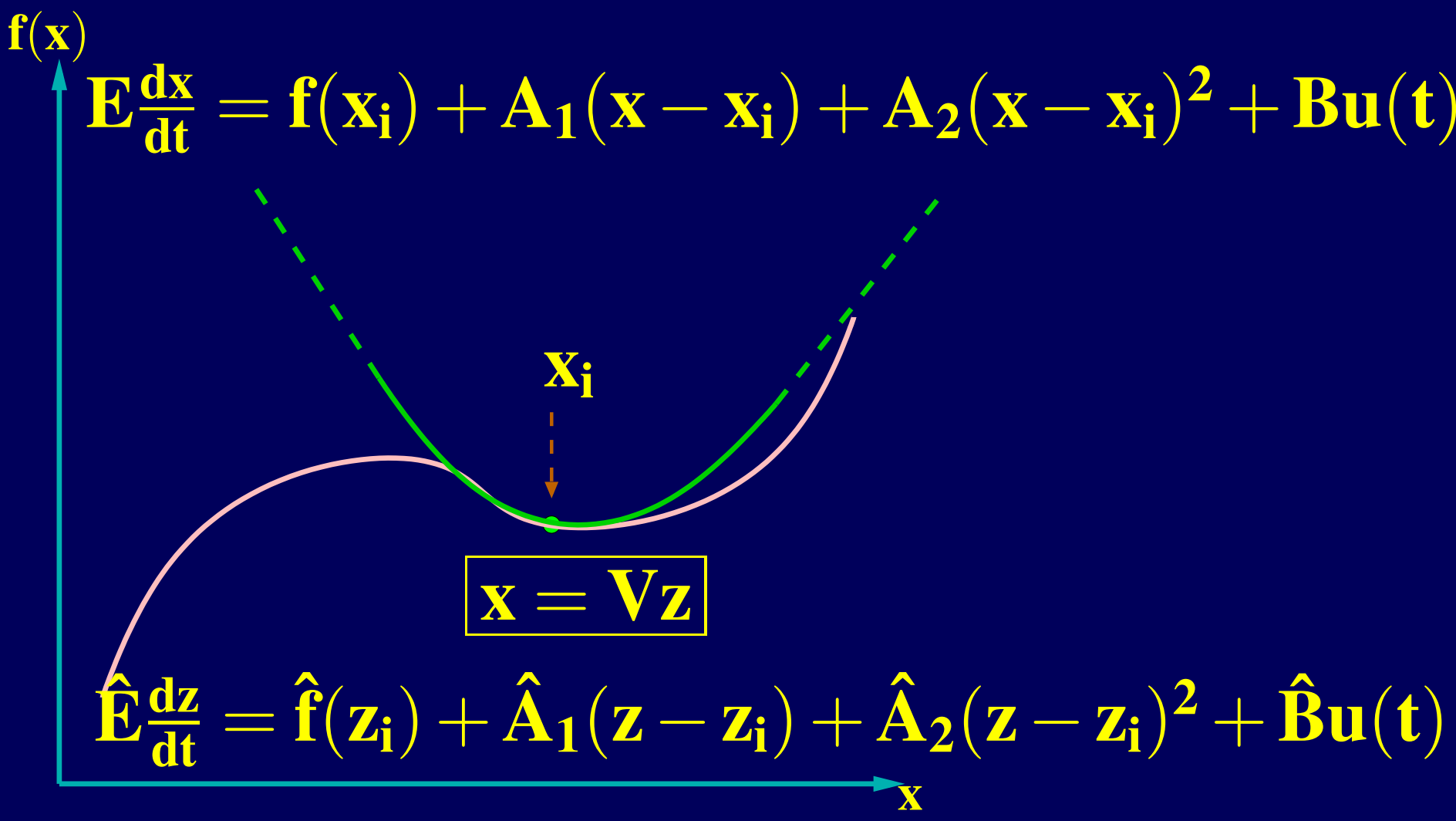




- Large signal clipping
- Must capture strong nonlinearities

Polynomial Reduction

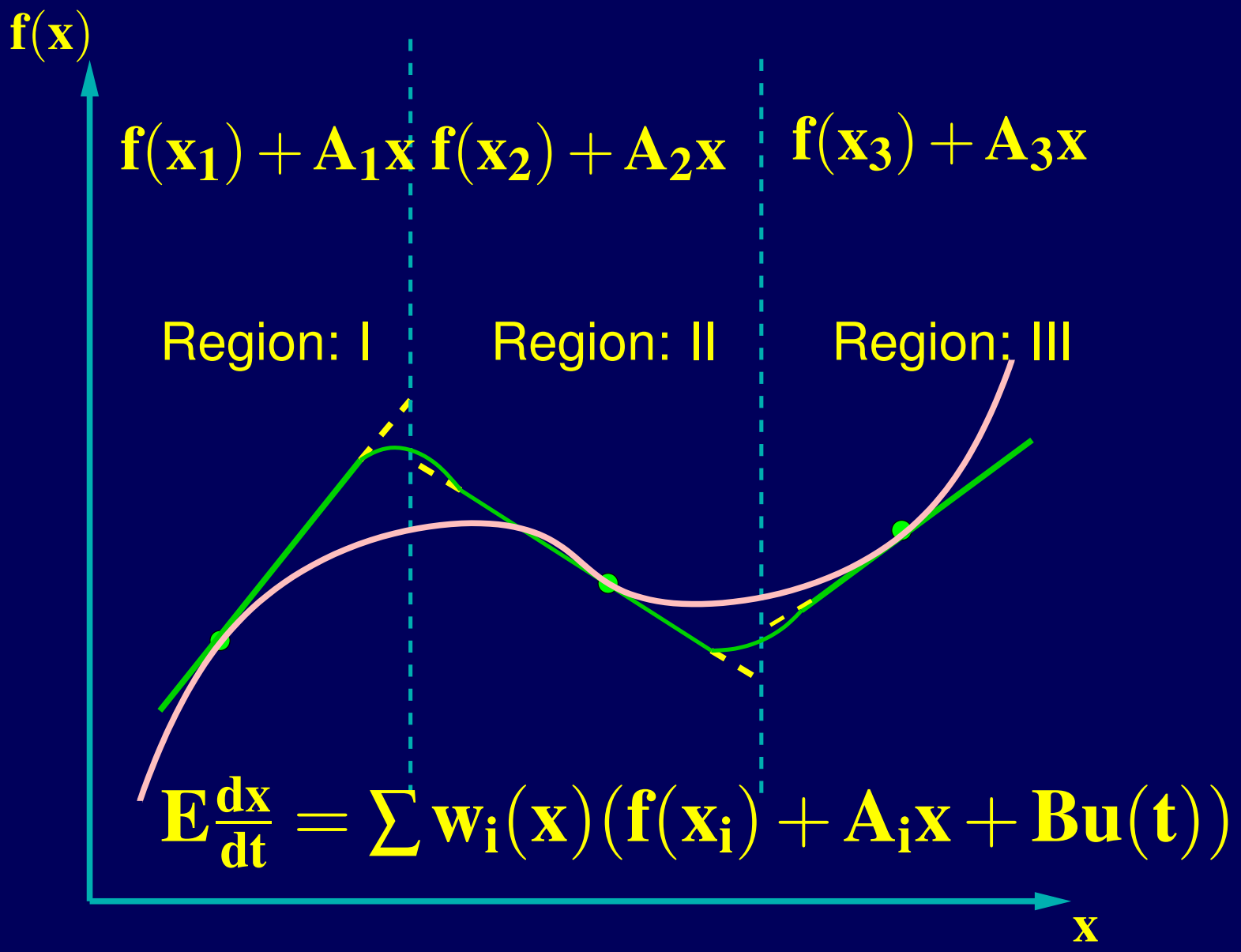
$$\mathbf{E}\frac{\mathbf{dx}}{\mathbf{dt}} = \mathbf{f}(\mathbf{x_i}) + \mathbf{A_1}(\mathbf{x} - \mathbf{x_i}) + \mathbf{A_2}(\mathbf{x} - \mathbf{x_i})^2 + \mathbf{Bu}(\mathbf{t})$$



$$\hat{\mathbf{E}}\frac{\mathbf{dz}}{\mathbf{dt}} = \hat{\mathbf{f}}(\mathbf{z_i}) + \hat{\mathbf{A}}_1(\mathbf{z} - \mathbf{z_i}) + \hat{\mathbf{A}}_2(\mathbf{z} - \mathbf{z_i})^2 + \hat{\mathbf{B}}\mathbf{u}(\mathbf{t})$$

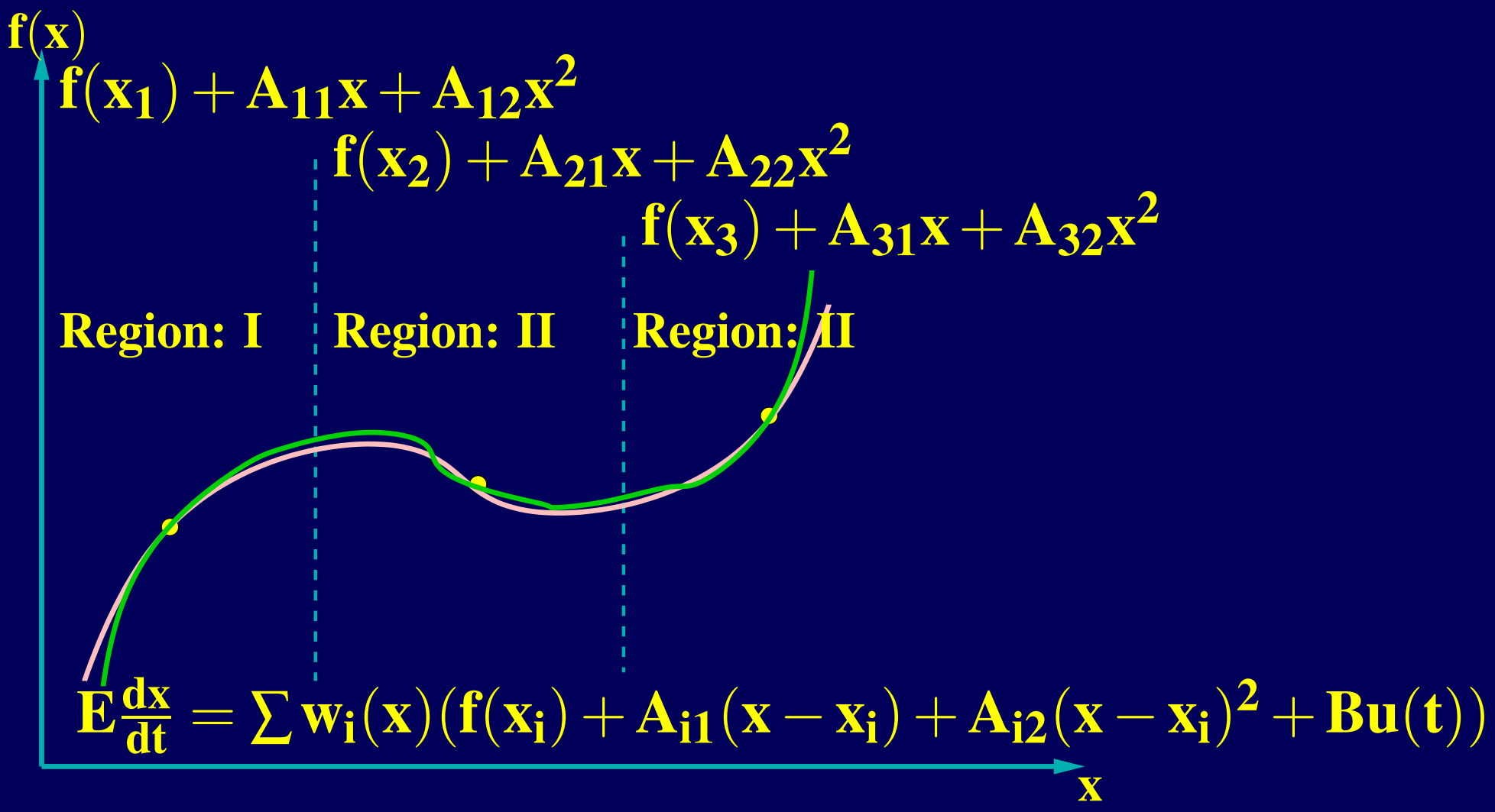
- **Good for small distortion, Poor for large swing**

Piecewise Linear MM



$$\mathbf{E}\frac{\mathbf{dx}}{\mathbf{dt}} = \sum \mathbf{w_i}(\mathbf{x})\left(\mathbf{f}(\mathbf{x_i}) + \mathbf{A_i x} + \mathbf{Bu}(\mathbf{t})\right)$$

Piecewise Poly MM



- Good for small distortion, also good for large swing

Nonlinear MM Results

Transient simulation of $1s$, measured on Linux/Matlab

Transmission Line (27 regions): $u(t) = 2sin(2\pi t) + sin(10\pi t)$			
Model Type	Model Size	Gen. Time [s]	Runtime [s]
Full	100	—	8.44
Reduced PWL	10	1.95	7.31
Reduced PWP	10	20.1	10.91
Cascade Amplifier (17 regions): $u(t) = 3 + 10^{-3}(sin(4\pi t) + sin(10\pi t))$			
Full	50	—	29.7
Reduced PWL	10	10	7.35
Reduced PWP	10	21.3	10.71

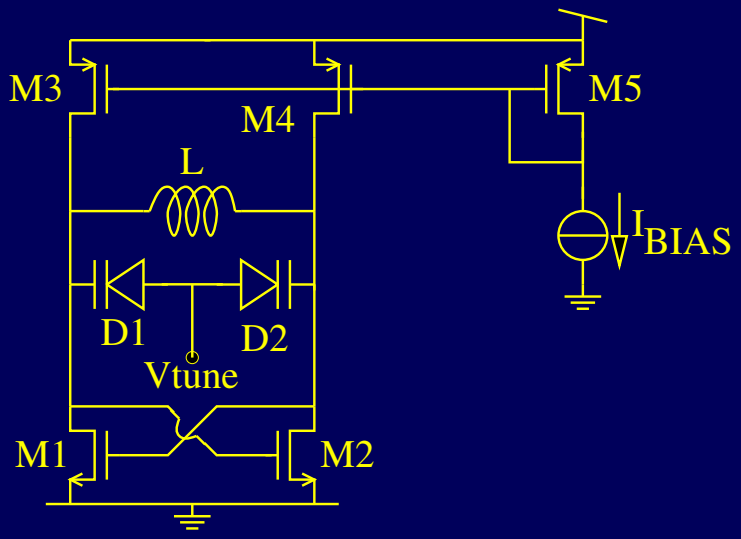
Linear Time Varying MM

- Useful abstraction for some nonlinear systems
  - mixers, switching filters, samplers, DC/DC converters, ...
  - Leverage LTI methods (Krylov, TBR, ...)
  - frequency translation/TD nonlinear sampling captured
  - signal-path nonlinearities **not** captured
- Input-output relationship linear
  - but **not time-invariant**

LTV MM on RF Mixer

- I-channel mixer and buffer block (Lucent ME W2013 RFIC)
- 360 nodes, signal upto 80KHz, LO at 178MHz
- LTV macromodel accuracy (**Time-Varying Pade**)
  - size 2: upconversion xfer fn matches to 300kHz
  - size 10: upconversion xfer fn matches to 400MHz!
- **Speedup more than 500**

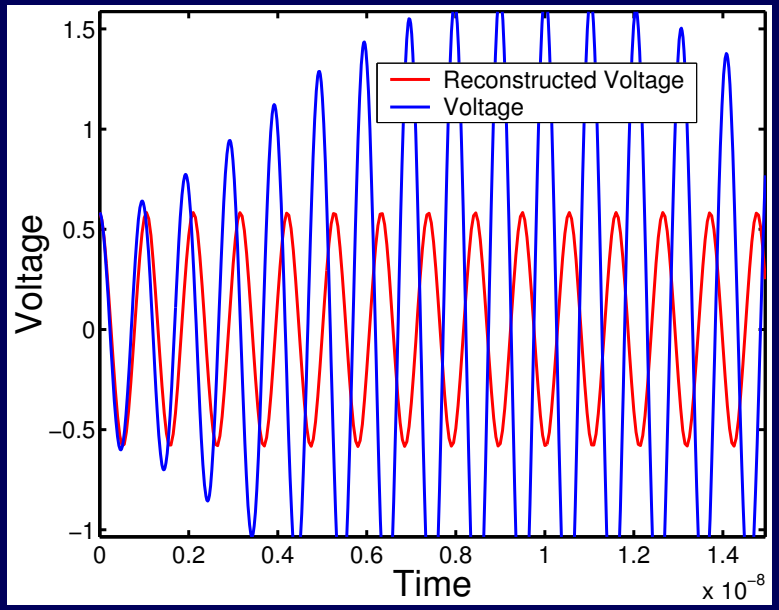
Oscillators: Nonlinear MM

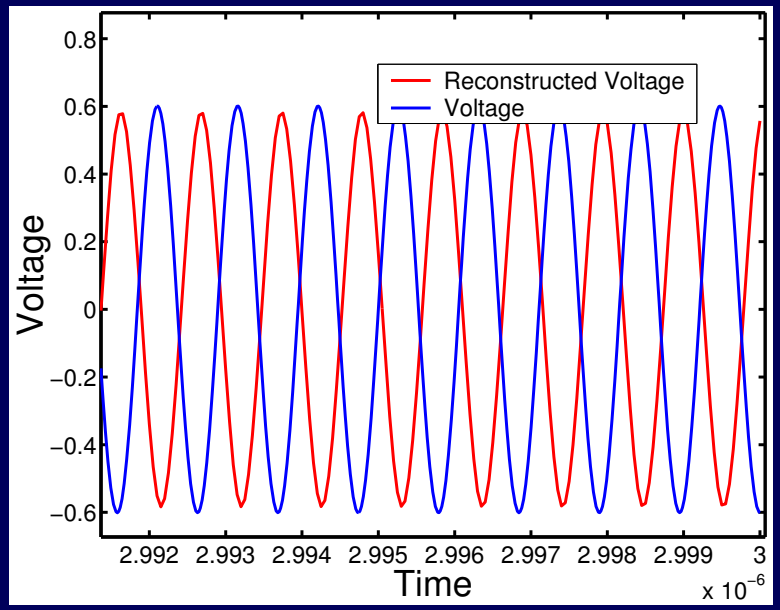


- **Critical in communication system designs**
  - VCOs, PLLs, LOs, synchronization, ...

- **Difficult for SPICE**: Inaccurate+extremely time-consuming
- Complex autonomous dynamics
- Existing hand-based macromodels miss qualitative phenomena
  - **injection locking**
- **Automated nonlinear MM**...

Osc MM captures injection locking





Unlocked regime

Locked regime

65x times speedup (for 2-node ckt); much greater for bigger oscillators

Nonlinear MM Progress

- Weak: JR (98), JRP (99-00), Li/Pileggi (NORM, 03)
- Strong: Rewienski/White (99-00), Dong/JR (03)
- LTV: JR/JRP (97)
- Oscillators: Li/JR (03)
- **Pockets of progress**
  - Not comprehensive like LTI
  - General problem **very difficult**
  - Dimensionality explosion (polynomial order, # regions)

Summary/Conclusions

- Automated MM **will** become practical
  - future system designs need it
  - (still) young area, much potential
- Hard problem: no single method will solve it all
  - pockets of elegant, useful, broadly applicable mathematical methods...
  - ...plus application-specific, roll-up-your-sleeves methods
  - Need to patch together **all approaches for useful, practical solutions**

Summary/Conclusions

- **Common, open, easy-to-use infrastructure** important: coalesce everyone's contributions
  - Significantly more complicated algorithms, better structuring, modularity **needed**
  - Open standards: avoid further balkanization of analog EDA

Summary/Conclusions

- Litmus test:

  Designer acceptance and involvement

  "Despite all of the benefits associated with analog top-down design, there remains a strong resistance against adopting this methodology. Many analog designers (at least so far) are content to maintain the status quo. Because most of the tools are new, many designers are unaware of their availability. This lack of awareness is further compounded by a natural resistance to change long-established procedures. Additionally, there's a learning curve associated with the new analog tools." - EE Times, 2001

Acknowledgments

- Joel Phillips, Ning Dong
- Ken Kundert, Jacob White, Peng Li, Larry Pileggi, Rob Rutenbar
- many others